Search Notes

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Application/Control I	No.

10/614,876 Examiner

Jeffrey J. Chow

Applicant(s)/Patent under Reexamination

CAO ET AL.

Art Unit

2672

	SEARCHED		
Class	Subclass	Date	Examiner
345	442, 420, 619	11/2/2005	JJC
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INTERFERENCE SEARCHED			
Subclass	Date	Examiner	

SEARCH N (INCLUDING SEARC)
	DATE	EXMR
"quadratic bezier" and flatness	11/2/2005	nc
bezier and bisection	11/2/2005	'nc
Did an inventor search No double patenting	10/27/2005	nc
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